Se	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/639,445	NAKAGAWA ET AL.	
Examiner	Art Unit	
Harold Kim	2182	

	SEARCHED		
Class	Subclass	Date	Examiner
710	5, 2, 69	6/29/2005	НК
712	32, 35	6/26/2005	HK
711	147	6/29/2005	HK
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	5	6/29/2005	нк
712	32, 35	6/29/2005	НК

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT, USPGPUB, JPO, EPO, IEEE, NPL, see attached search note	6/29/2005	нк	
Inventor search on eDAN including USPAT# 6,353,863 and 6,643,713; consulted w/ Primary Christopher Shin, and SPE Dov Popovici	6/29/2005	нк	

Amlel Q: